# Beam test with irradiated digital ROCs first results

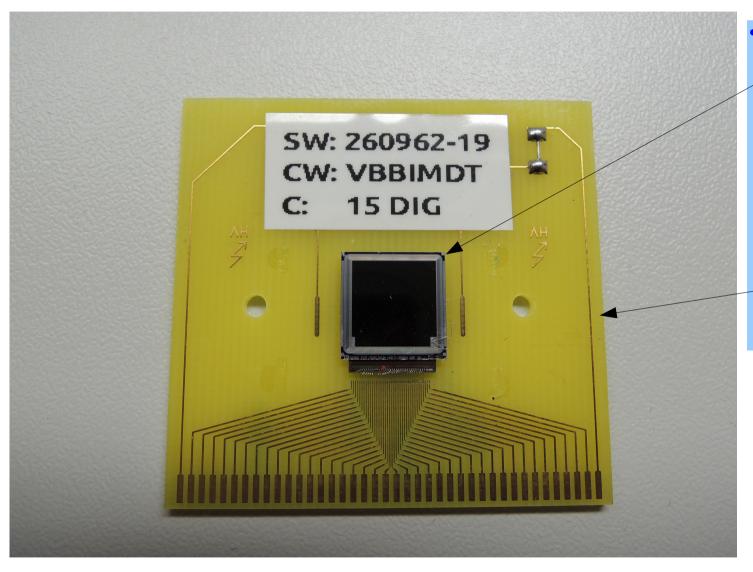
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Daniel Pitzl, Valentina Sola, Simon Spannagel
DESY and Uni HH

Hamburg CMS Tracker Upgrade meeting, 12.4.2013



- irradiation at CERN PS: Oct 28-30, 2012
- beam test at DESY T21: April 1-7, 2013
  - cooling
  - first results

### CMS pixel single chip module



- Single chip module:
  - ► Si: 10×10 mm<sup>2</sup>
  - Indium bump bonded at PSI
  - Glued and wire bonded to carrier printed circuit board
  - PCB:  $40 \times 40 \text{ mm}^2$

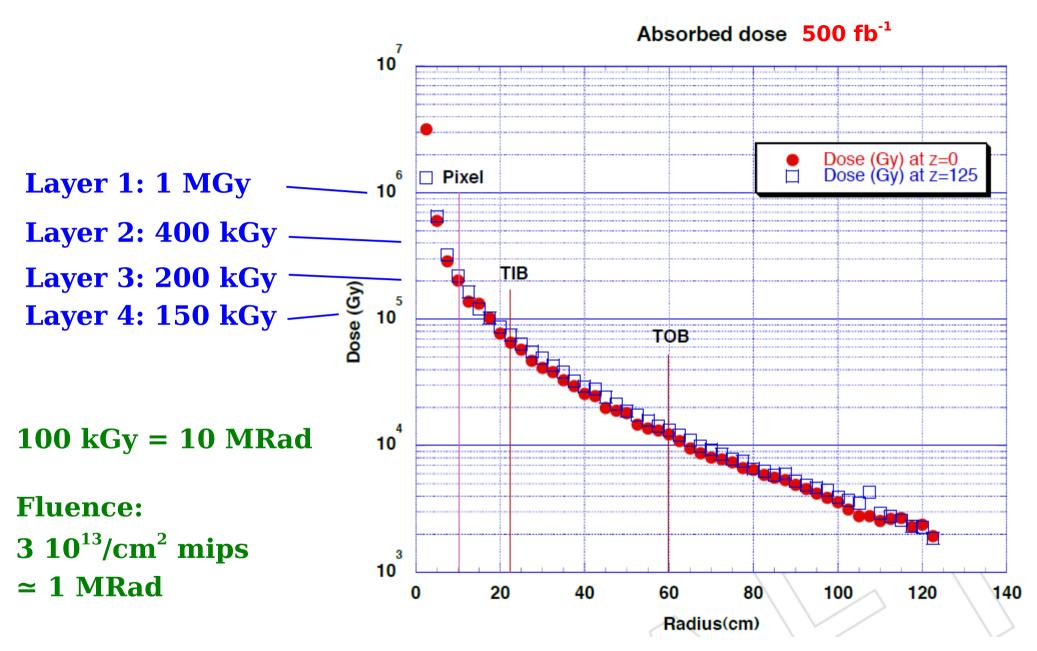
PCB with minimal metal (activation)

### **CERN PS irradiation**

- CERN PS IRRAD 1: 24 GeV protons
- psi46dig chip 202 with sensor = sample 1785
  - ► 29.10.2012, 9:26 16:00,  $\mathbf{F} = \mathbf{0.91} \ \mathbf{10^{14}/cm^2} \ (\pm 7.4\%)$
  - $\rightarrow$  D = 3 Mrad
- psi46dig chip 203 with sensor = sample 1786
  - ▶ 28./29.10.2012, 17:05 8:45,  $F = 2.27 \cdot 10^{14}$ /cm<sup>2</sup>
  - $\triangleright$  29.10.2012, 9:26 16:00, F = 0.91 10<sup>14</sup>/cm<sup>2</sup>
  - ▶ 30.10.2012, 9:27 12:52,  $F = 0.60 \ 10^{14}$ /cm<sup>2</sup>
  - ► total  $\mathbf{F} = 3.77 \ \mathbf{10^{14}/cm^2} \ (\pm 7.6\%)$
  - **▶ D** = 13 Mrad
- stored at -20°C

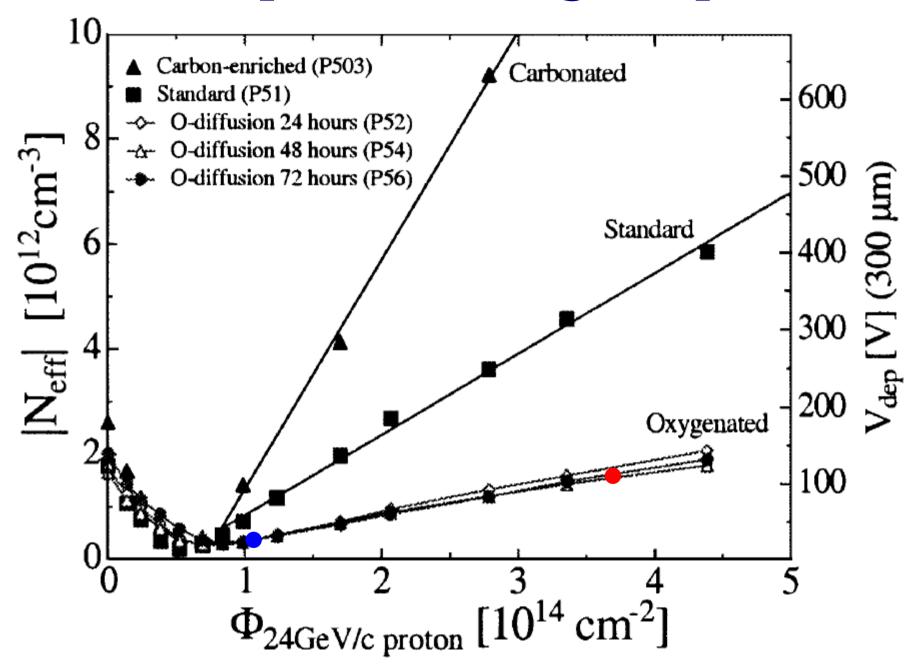
https://irradiation.web.cern.ch/irradiation/Dosimeter/Sets-2012.htm

### **Tracker radiation dose**



Pixel upgrade TDR 2012

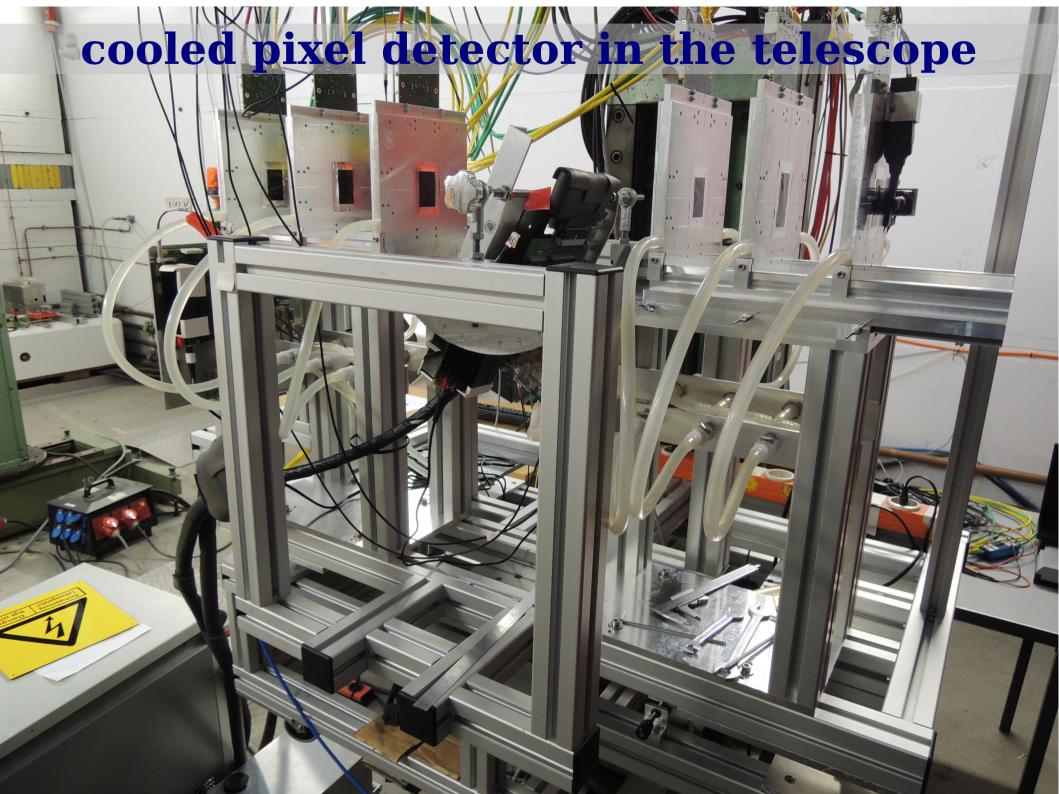
### silicon depletion voltage vs p fluence

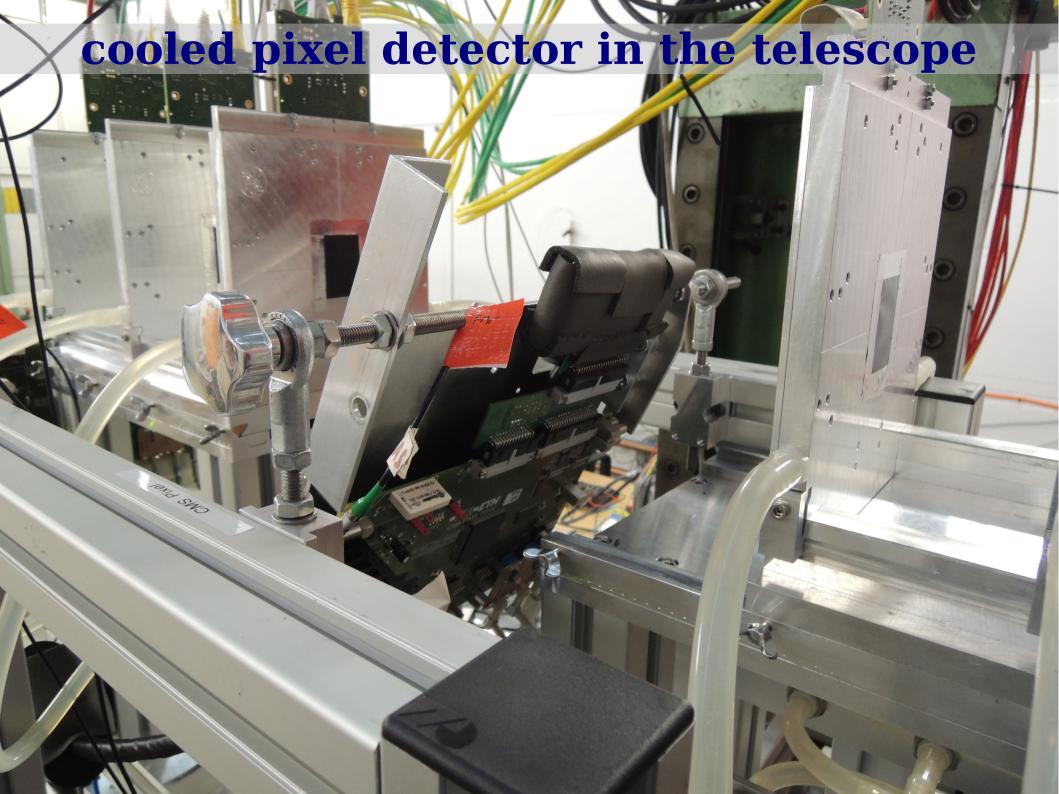


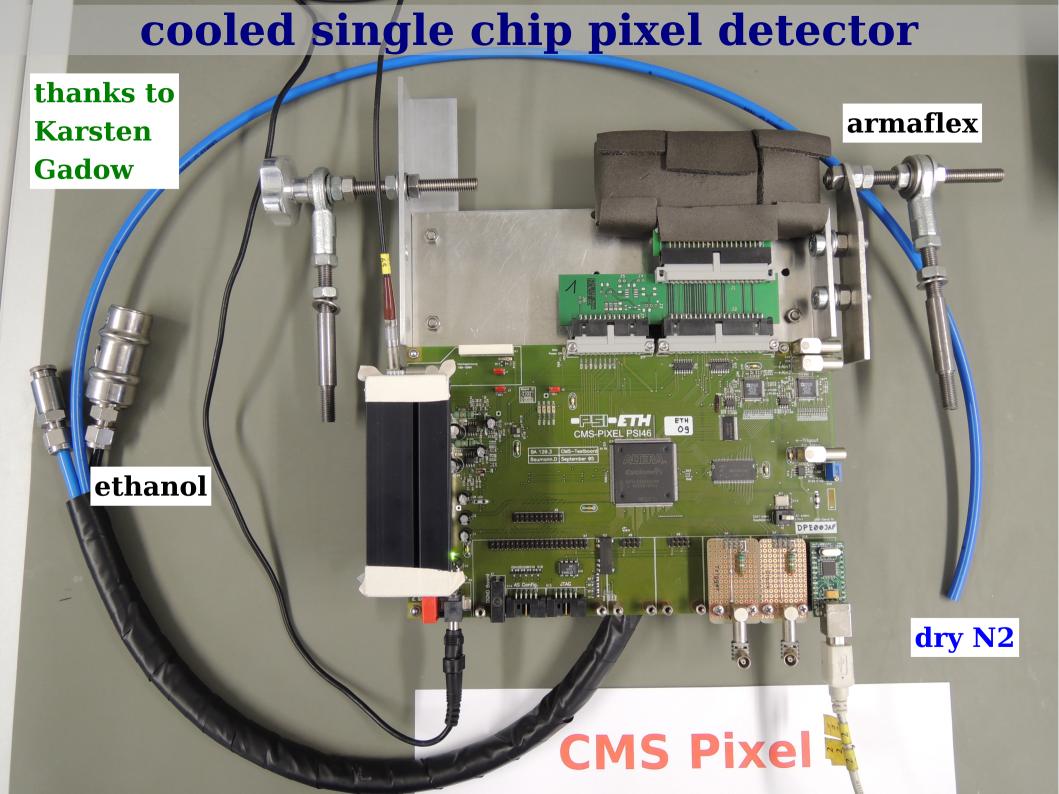
G. Lindstroem NIM A 512 (2003) 30











### Beam test program

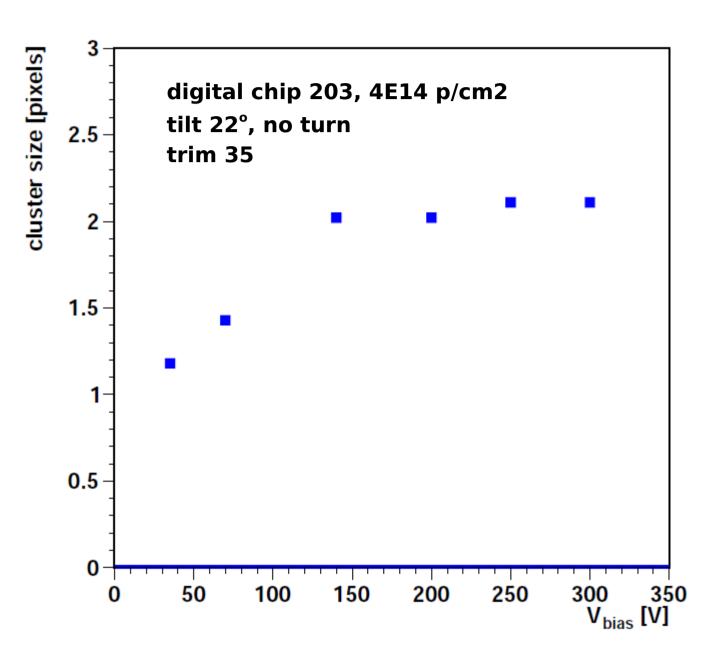
- fixed: 4.4 GeV, ~600 Hz, Mimosa threshold 6
- irradiated psi46dig chip 202:
  - ▶ no cooling
  - ▶ tilt 19°, later add turn 28°
  - bias scan at low threshold
  - threshold scan at high bias
- irradiated psi46dig chip 203:
  - cooling with chiller at -15°C
  - bias scan and threshold with tilt and turn
  - bias and tilt scan at low threshold, no turn

```
https://docs.google.com/spreadsheet/ccc?
key=0AsHfEWLQILQVdDRodWt1dTVWRXkyd25NWlNNX25haUE#gid=0
```

# Results from chip 203: 4E14 p/cm2

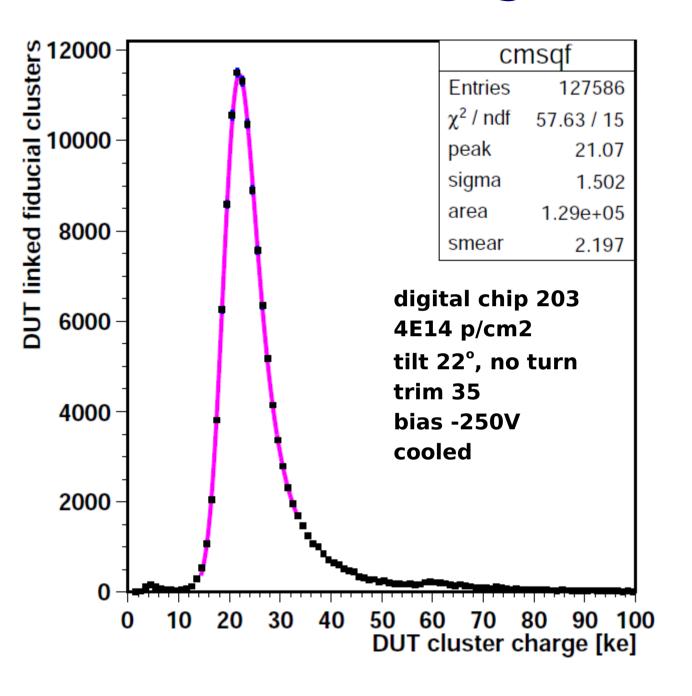
- depletion voltage
- resolution
- efficiency

### cluster size vs bias voltage



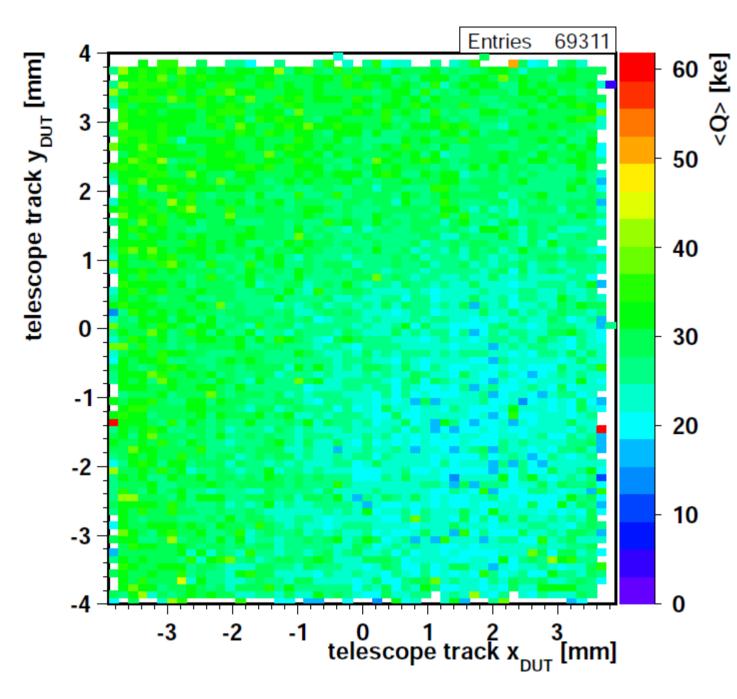
- psi46dig chip 203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 35
  - ► 22° tilt, no turn
- full depletion around 150 V

## cluster charge distribution



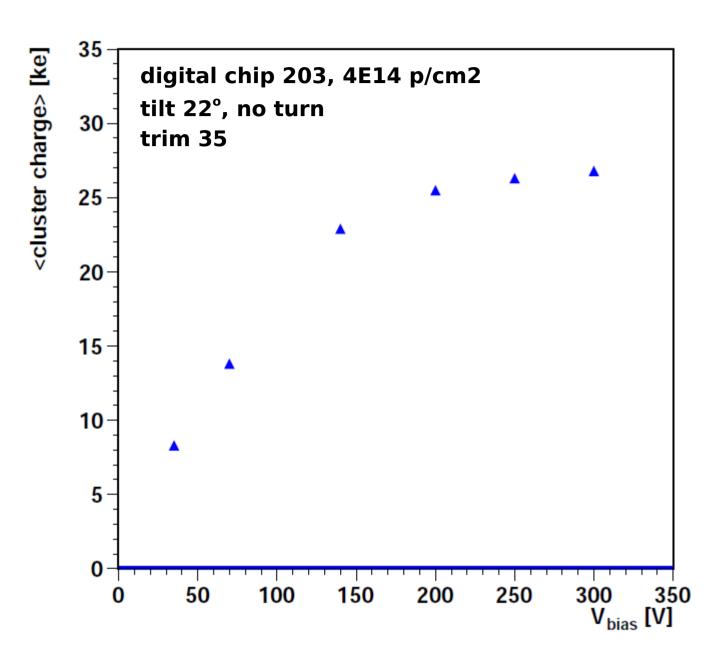
- digital chip 203:
  - ► 13 MRad
  - ► Ia 25 mA, trim 35
  - ▶ bias -250V, cooled
  - ▶ tilt 22°, no turn
- Gain calibration: cooled, Weibull fit, assume 50e/DAC
- - peak at 21.1 ke a little low
  - width as before

### charge map



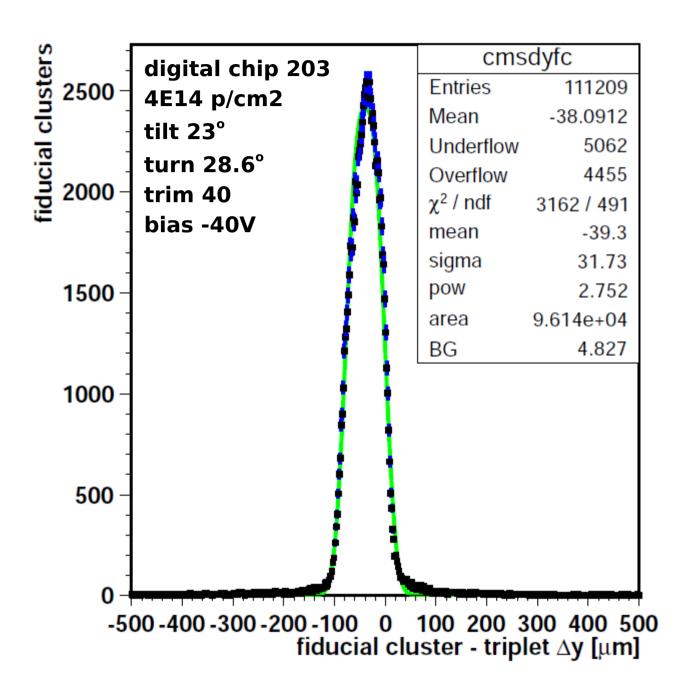
- psi46dig chip203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 40
  - ► 23° tilt, turn 29°
  - Weibull gain calibration
- valley in lower left quadrant:
  - sensor or ROC feature?

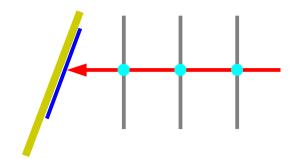
### cluster charge vs bias voltage



- psi46dig chip 203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 35
  - ► 22° tilt, no turn
- full depletion?

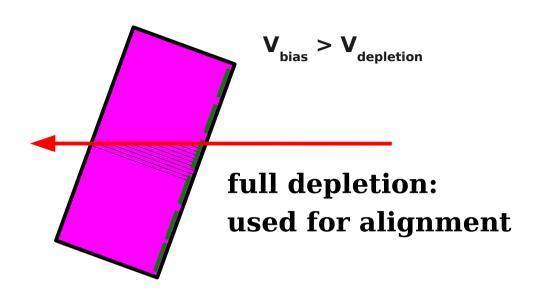
### track-cluster residuals



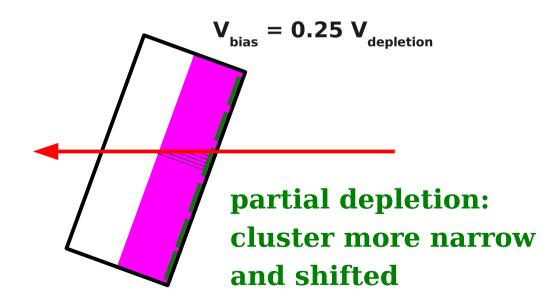


- digital chip 203:
  - ► 13 MRad
  - ► Ia 25 mA, trim 40
  - **▶** bias -40V
  - ► tilt 23°, turn 29°
- partial depletion and tilt:
  - cluster shifted

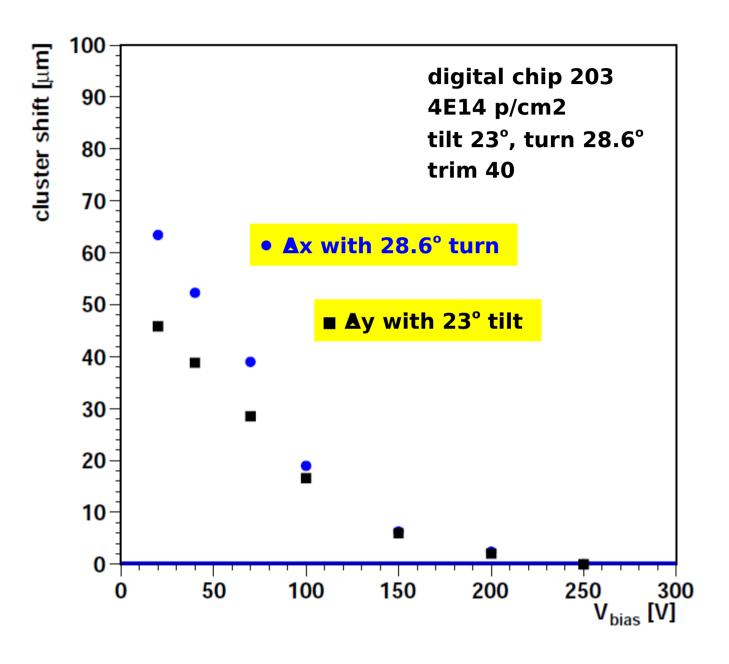
### depletion depth



irradiated: type inversion, depletion starts from pixel side



### cluster shift vs bias voltage

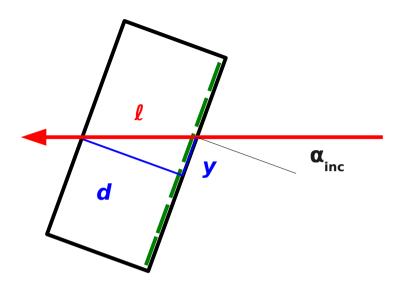


- psi46dig chip203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 40
  - ► 23° tilt, turn 29°
- partial depletion
  - effective depth changes
- and tilt:
  - cluster position gets shifted

### to do

- use cluster shift as function of bias and angle
  - to map out the depletion depth
- check:
  - uniformity across the sensor
  - $\rightarrow$  d  $\sim$   $\sqrt{V_{\text{bias}}}$

# angles

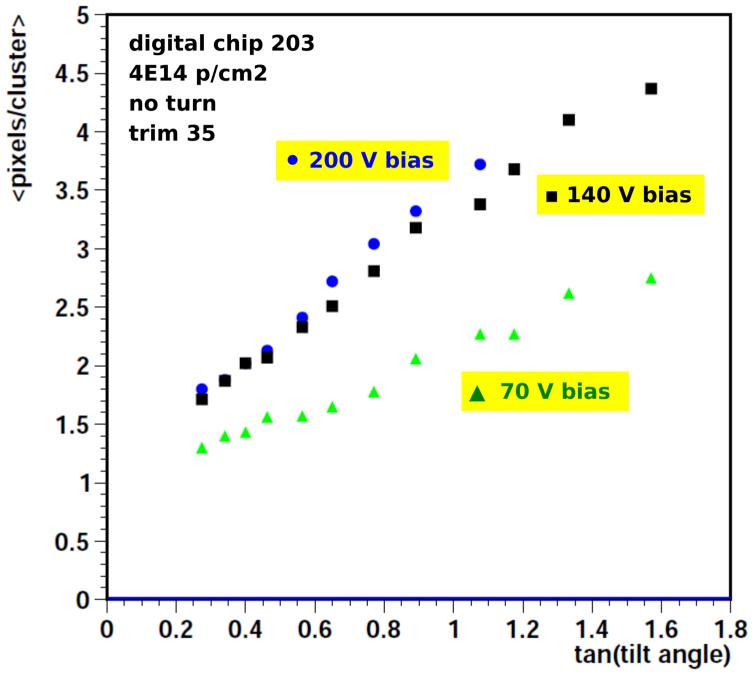


sensor thickness  $d = 285 \mu m$ 

path length:  $\ell = d / \cos \alpha$ 

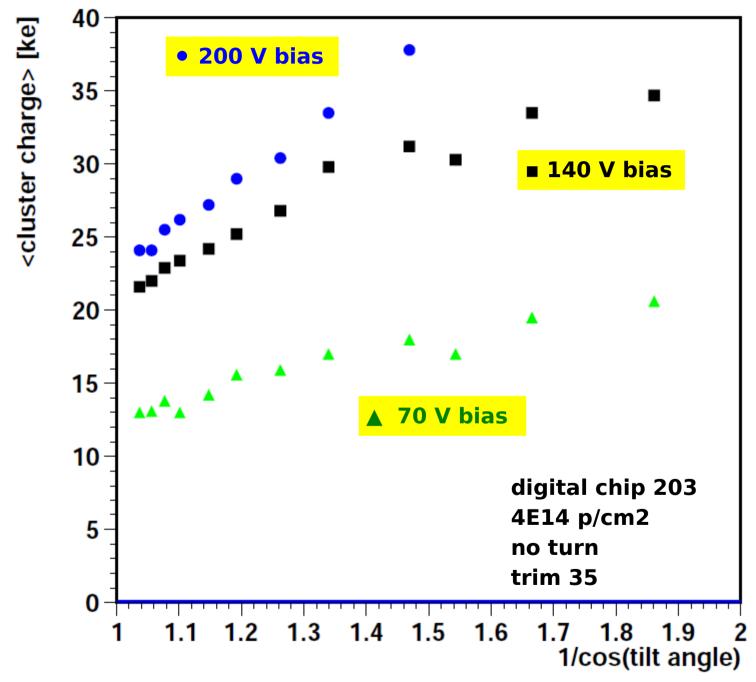
cluster width:  $y = d \tan \alpha$ 

### cluster size vs tilt angle and bias



- psi46dig chip 203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 35
  - vary tilt, no turn
- cluster size scales with geometry:
  - $\rightarrow tan(\alpha_{tilt})$
- cluster size saturated at 140 V
  - ► full depletion

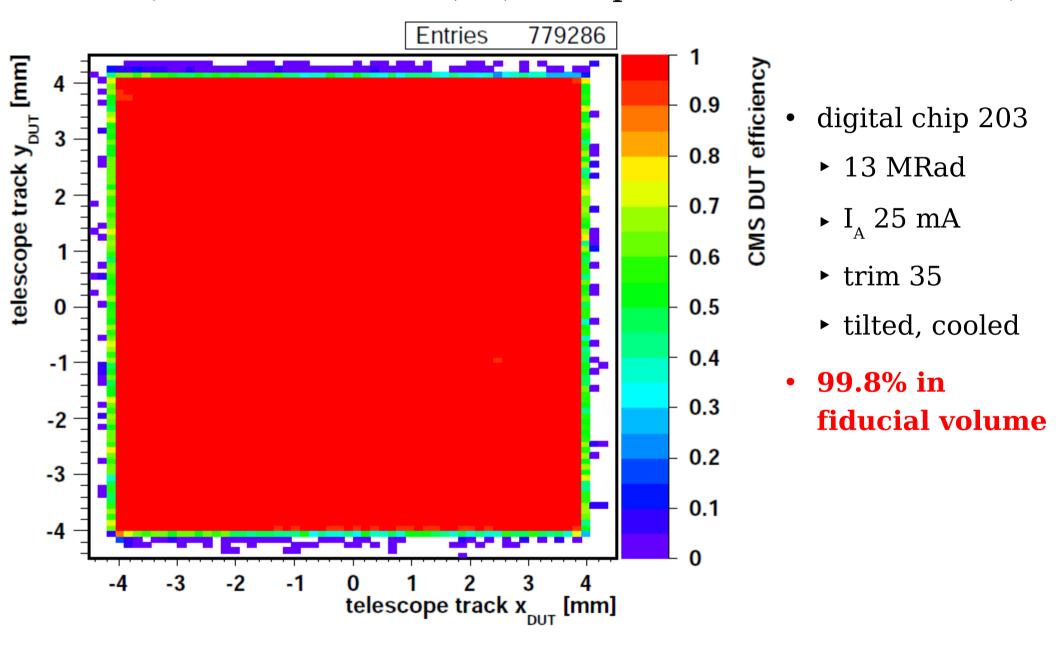
### cluster charge vs tilt angle and bias



- psi46dig chip 203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 35
  - vary tilt, no turn
- cluster charge scales with path length in silicon:
  - $\sim 1/\cos(\alpha_{\rm tilt})$

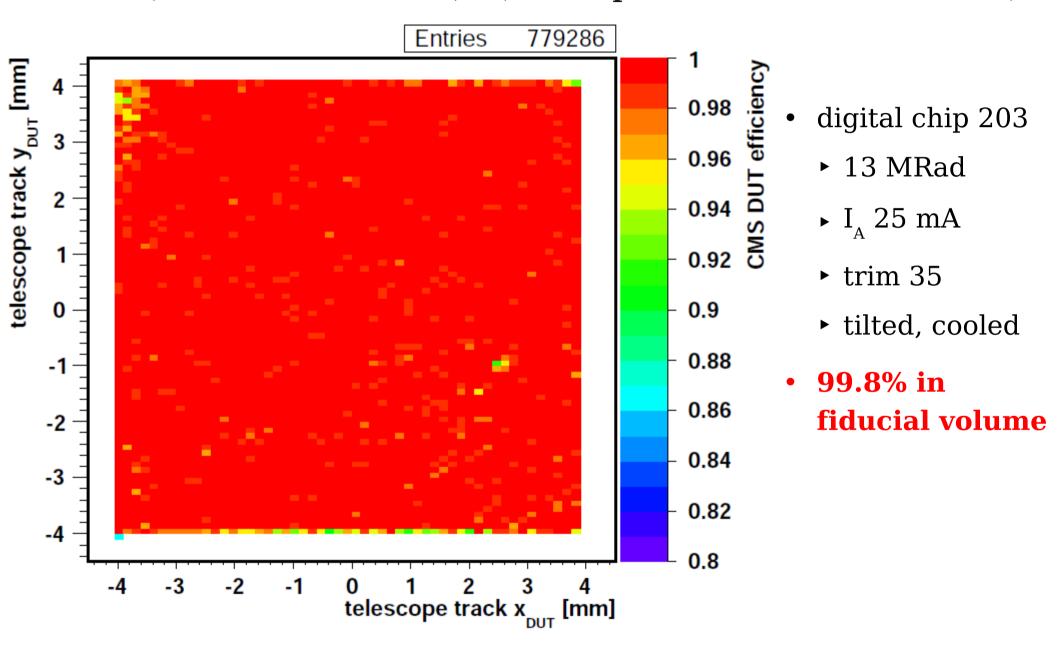
### efficiency map

eff = (DUT linked clusters) / (telescope tracks with REF cluster)

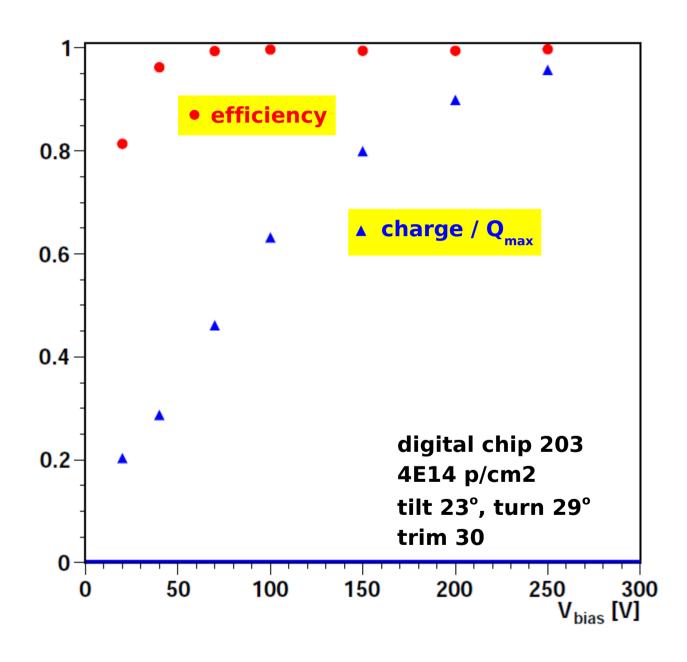


### efficiency map (zoomed)

eff = (DUT linked clusters) / (telescope tracks with REF cluster)

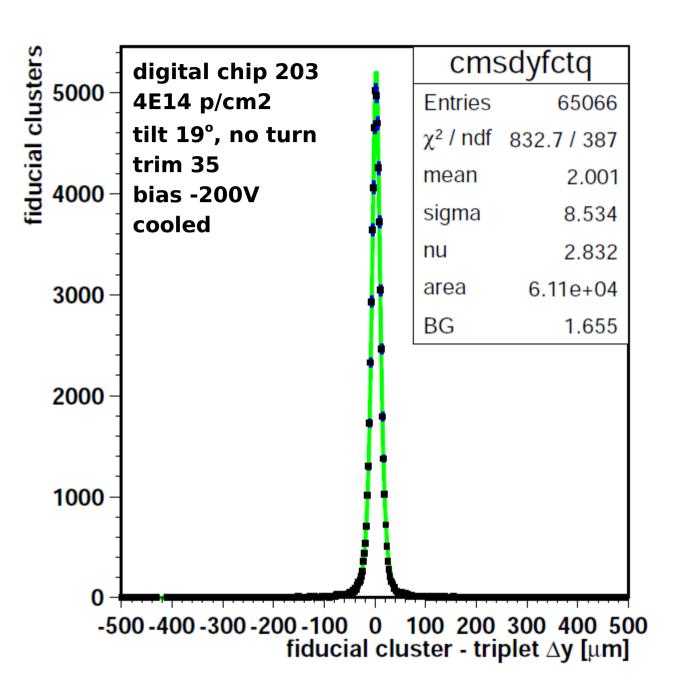


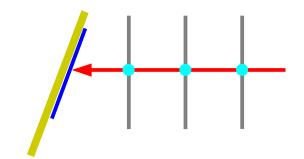
### efficiency vs bias voltage



- psi46dig chip 203:
  - ► 13 MRad
  - ► Ia 25 mA
  - ▶ trim 40
  - ► tilt 23°, turn 29°
- fully efficient down to 70 V bias
  - half the charge is enough!

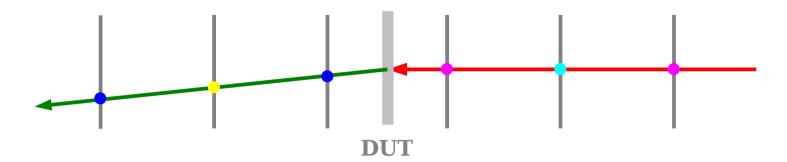
### resolution

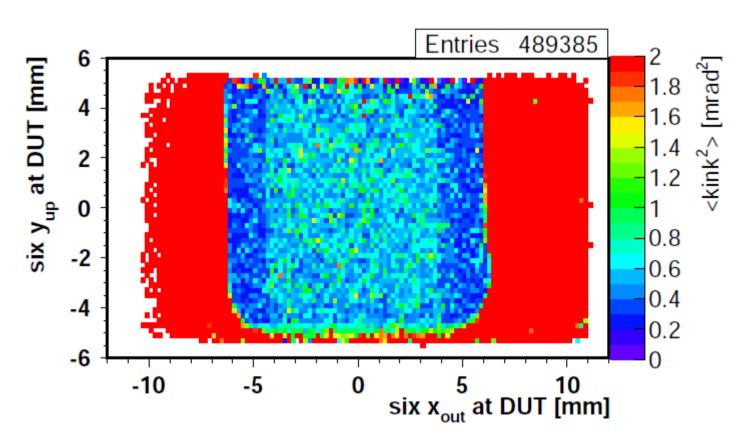




- digital chip 203:
  - ► 13 MRad
  - ▶ Ia 25 mA, trim 35
  - ▶ bias -200V, cooled
  - ▶ tilt 19°, no turn
- residual to track:
  - sigma 8.5 μm
  - subtract telescope resolution 4.6 μm
  - CMS pixel row resolution 7 μm
  - ▶ like before

### **DUT** cooling material map





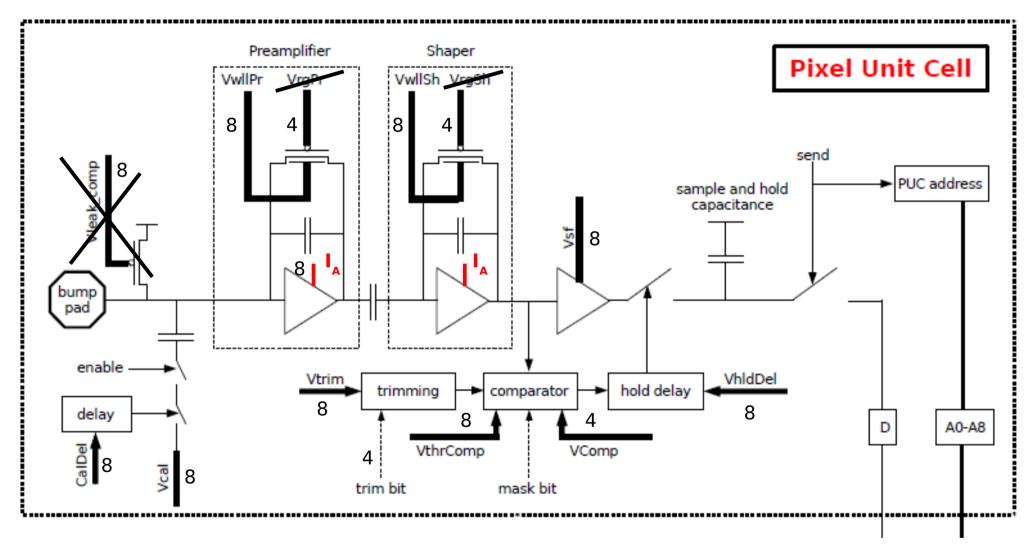
- scattering angle at the DUT
  - from upstream and downstream tracks
- Copper cooling block has ±6 mm opening
- DUT on PCB visible

### **summary**

- beam test with irradiated digital ROCs done
  - with cooling
- digital ROC after 13 Mrad (4E14 p/cm2 = lifetime dose for layer 4):
  - depletion voltage about 140 V
  - fully efficient above 70 V (with low threshold)
  - similar resolution as unirradiated: 7 μm
- next:
  - more analysis: chip202, resolution for partially depleted detectors
  - compare to pre-irradiation beam test (Aug and Sep 2012)
  - simulation
  - publish

# Back up

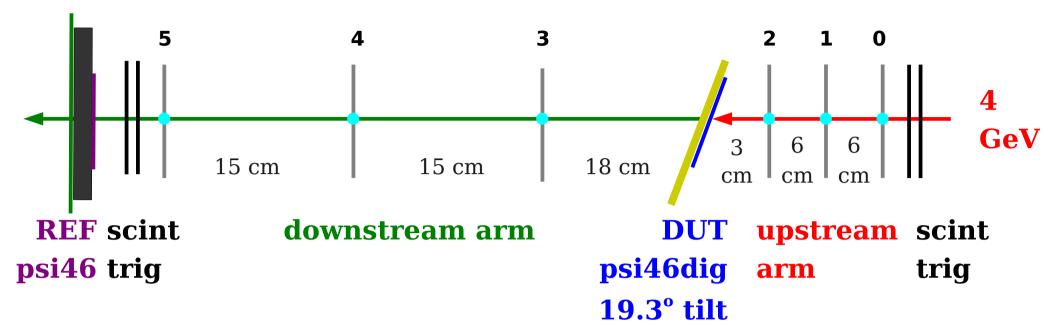
## psi46dig pixel unit cell



adjustable by programmable DAC

supplied by analog current

### test beam set up



- Upstream arm 0-1-2:
  - ► as close as possible to DUT: 4.8 µm extrapolation error (at 4 GeV)
- DUT = single chip module, tilted by  $19.3^{\circ}$  = atan( $100 \,\mu\text{m}$  /  $285 \,\mu\text{m}$ )
- Downstream arm 3-4-5:
  - equally spaced between DUT and REF
- REF = single chip module for timing, as close as possible behind scint
- trigger: 4-fold scintillator coincidence, 2×1 cm<sup>2</sup> area

# psi46dig pixel readout chip

